

LF353

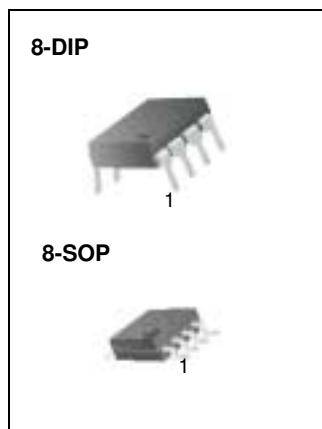
Dual Operational Amplifier (JFET)

Features

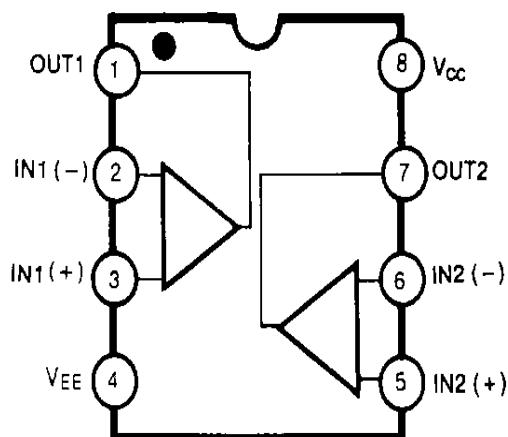
- Internally trimmed offset voltage: 10mV
- Low input bias current: 50pA
- Wide gain bandwidth: 4MHz
- High slew rate: 13V/ μ s
- High Input impedance: $10^{12}\Omega$

Description

The LF353 is a JFET input operational amplifier with an internally compensated input offset voltage. The JFET input device provides wide bandwidth, low input bias currents and offset currents.

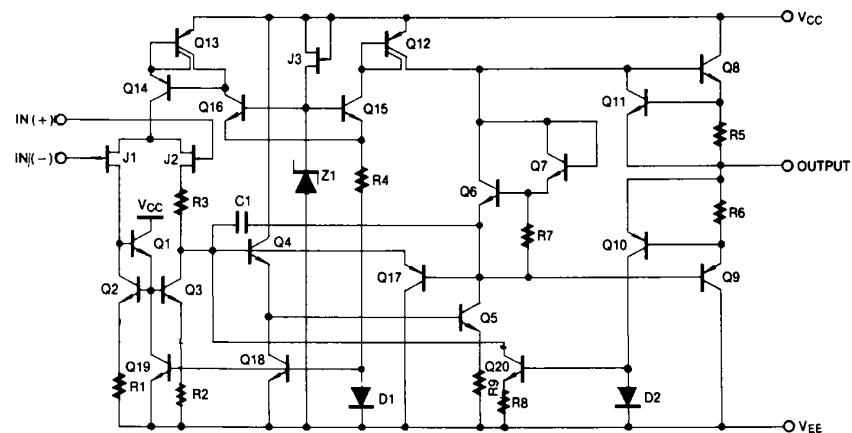


Internal Block Diagram



Schematic Diagram

(One Section Only)



Absolute Maximum Ratings

| Parameter | Symbol | Value | Unit |
|-------------------------------|----------------------|------------|------|
| Power Supply Voltage | V _{CC} | ±18 | V |
| Differential Input Voltage | V _{I(DIFF)} | 30 | V |
| Input Voltage Range | V _I | ±15 | V |
| Output Short Circuit Duration | - | Continuous | - |
| Power Dissipation | P _D | 500 | mW |
| Operating Temperature Range | T _{OPR} | 0 ~ +70 | °C |
| Storage Temperature Range | T _{STG} | -65 ~ +150 | °C |

Electrical Characteristics

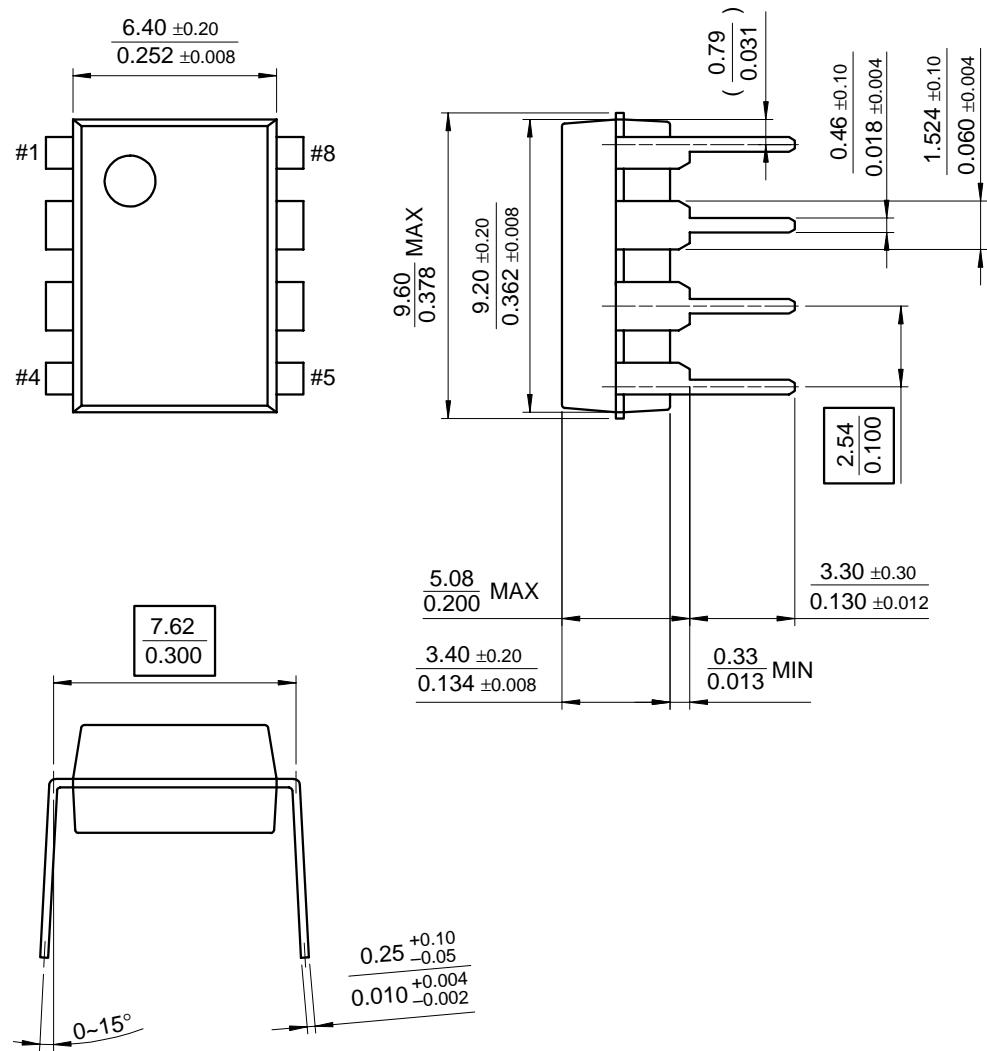
(V_{CC} = +15V, V_{EE} = -15V, T_A = 25 °C, unless otherwise specified)

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit | |
|--------------------------------|----------------------|--|-----------------------------|------------------|------|--------|--------|
| Input Offset Voltage | V _{IO} | R _S =10KΩ | - | 5.0 | 10 | mV | |
| | | 0 °C≤T _A ≤+70 °C | - | - | - | - | |
| Input Offset Voltage Drift | ΔV _{IO} /ΔT | R _S =10KΩ | 0 °C≤T _A ≤+70 °C | - | 10 | - | μV/ °C |
| Input Offset Current | I _{IO} | | - | 25 | 100 | pA | |
| Input Bias Current | I _{BIAS} | | 0 °C≤T _A ≤+70 °C | - | 4 | nA | |
| | | | 0 °C≤T _A ≤+70 °C | - | 50 | 200 | pA |
| Input Resistance | R _I | - | - | 10 ¹² | - | Ω | |
| Large Signal Voltage Gain | G _V | V _{O(P-P)} = ±10V | 25 | 100 | - | V/mV | |
| | | R _L = 2KΩ 0 °C≤T _A ≤+70 °C | 15 | - | - | - | |
| Output Voltage Swing | V _{O(P-P)} | R _L = 10KΩ | ±12 | ±13.5 | - | V | |
| Input Voltage Range | V _{I(R)} | - | ±11 | ±15/-12 | - | V | |
| Common Mode Rejection Ratio | CMRR | R _S ≤ 10KΩ | 70 | 100 | - | dB | |
| Power Supply Rejection Ratio | PSRR | R _S ≤ 10KΩ | 70 | 100 | - | dB | |
| Power Supply Current | I _{CC} | - | - | 3.6 | 6.5 | mA | |
| Slew Rate | SR | G _V = 1 | - | 13 | - | V/μS | |
| Gain-Bandwidth Product | GBW | - | - | 4 | - | MHz | |
| Channel Separation | CS | f = 1Hz ~ 20KHz (Input referenced) | - | 120 | - | dB | |
| Equivalent Input Noise Voltage | V _{NI} | R _S = 100Ω f = 1KHz | - | 16 | - | nV/√Hz | |
| Equivalent Input Noise Current | I _{NI} | f = 1KHz | - | 0.01 | - | pA/√Hz | |

Mechanical Dimensions

Package

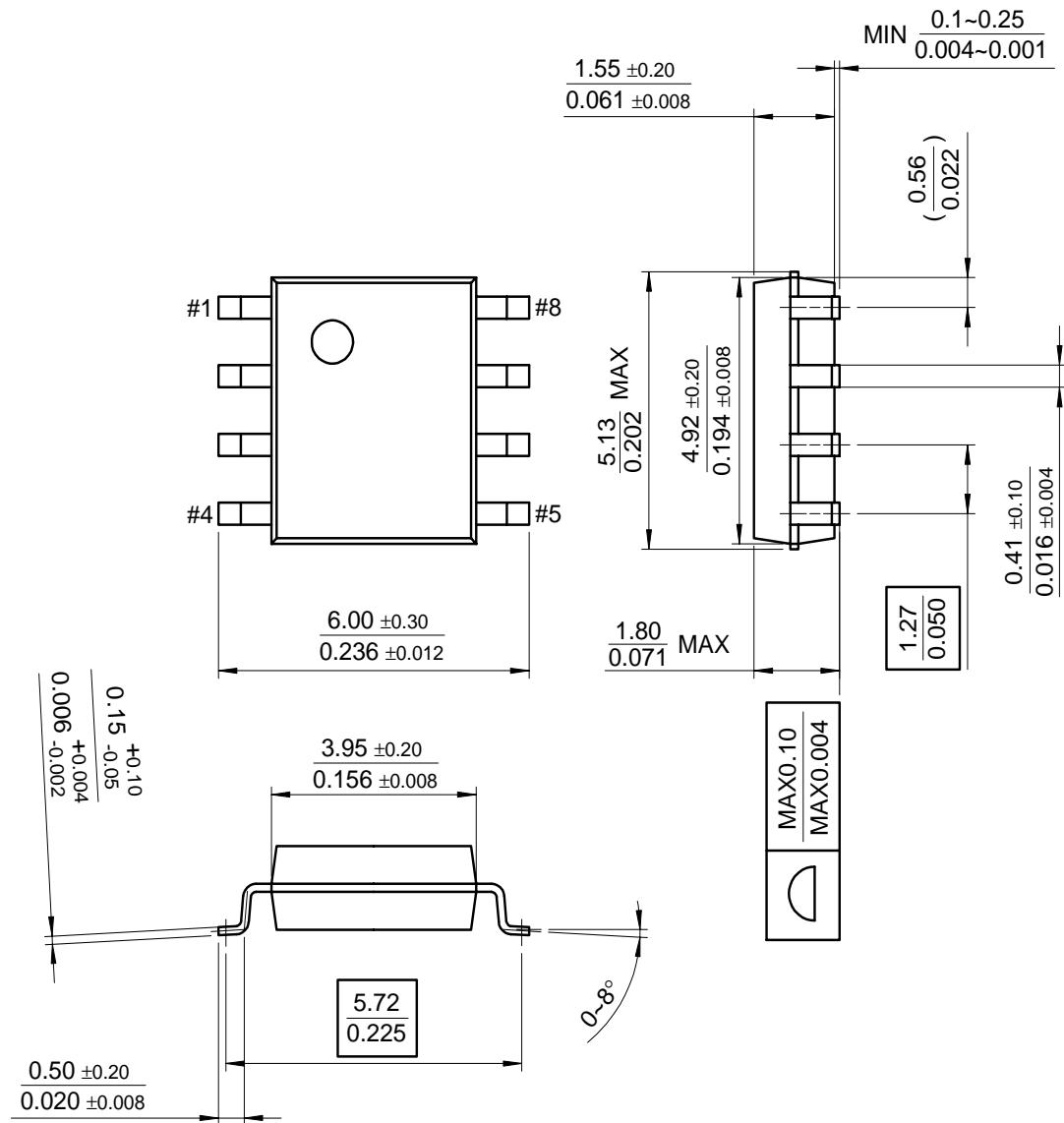
8-DIP



Mechanical Dimensions

Package

8-SOP



Ordering Information

| Product Number | Package | Operating Temperature |
|----------------|---------|-----------------------|
| LF353N | 8-DIP | 0 ~ + 70°C |
| LF353M | 8-SOP | |

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